

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/781,862	FUJIMAKI, KAZUHIRO	
Examiner	Art Unit	
Sin J. Lee	1752	

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Class	Subclass	Date	Examiner		
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	281.1				
	944				
	271.1				
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
Structure Searches for the compounds of CI.#5 & CI.#6	9-22 -05	SJL			
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